



PATENT  
Attorney Docket No. 02887.0257  
CUSTOMER NUMBER 22,852

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of:	)	
	)	
Inventor: Akira HAMAGUCHI <i>et al.</i>	)	Group Art Unit: 2623
	)	
Application No.: 10/687,828	)	Examiner: Not Assigned
	)	
Filed: October 20, 2003	)	
	)	
For: METHOD AND APPARATUS FOR	)	
DETERMINING DEFECT	)	
DETECTION SENSITIVITY DATA,	)	
CONTROL METHOD OF DEFECT	)	
DETECTION APPARATUS, AND	)	
METHOD AND APPARATUS FOR	)	
DETECTING DEFECT OF	)	
SEMICONDUCTOR DEVICES	)	

**Commissioner for Patents**  
**P.O. Box 1450**  
**Alexandria, VA 22313-1450**

Sir:

**PRELIMINARY AMENDMENT**

Prior to examination, please amend the above-identified application as follows:

**Amendments to the Specification** are included in this paper.

**Amendments to the Claims** are reflected in the listing of claims in this paper.

**Amendments to the Drawings** are included in the attached replacement drawing sheet. The amendments are discussed in this paper and are also illustrated in the attached annotated drawing sheet.

**Remarks** follow the amendment section of this paper.